

Full Bridge IGBT and MOSFET MTP Power Module



MTP

| PRODUCT SUMMARY | |
|--------------------------------------|---------------|
| HALF BRIDGE POWER MOSFET | |
| V_{DSS} | 650 V |
| $R_{DS(on)}$ typical at $I_D = 40$ A | 35 m Ω |
| I_D at $T_C = 80$ °C | 41 A |
| HALF BRIDGE WARP IGBT | |
| V_{CES} | 600 V |
| $V_{CE(on)}$ typical at $I_C = 25$ A | 2.18 V |
| I_C at $T_C = 80$ °C | 46 A |

FEATURES

- Generation 4 warp speed IGBT and power MOSFET technology
- HEXFRED® antiparallel diodes with ultrasoft reverse recovery
- Very low conduction and switching losses
- Operating frequency up to 100 kHz
- Designed and qualified for industrial level
- Material categorization: For definitions of compliance please see www.vishay.com/doc?99912


RoHS
COMPLIANT

BENEFITS

- Optimized for welding, UPS and SMPS applications
- Low EMI, requires less snubbing
- Direct mounting to heatsink
- PCB solderable terminals
- Very low stray inductance design for high speed operation

| ABSOLUTE MAXIMUM RATINGS | | | | | |
|-----------------------------------|----------------|---|-----------------|-------------|------------|
| PARAMETER | SYMBOL | TEST CONDITIONS | | MAX. | UNITS |
| Operating junction temperature | T_J | | | 150 | °C |
| Storage temperature range | T_{Stg} | | | - 40 to 150 | |
| V_{RMS} Insulation voltage | V_{ISOL} | AC 1.2 s | | 3500 | V |
| Q1, Q2 POWER MOSFET | | | | | |
| Drain to source voltage | V_{DSS} | | | 650 | V |
| Gate to source voltage | V_{GS} | | | 25 | |
| Pulsed drain current | $I_{DM}^{(1)}$ | | | 270 | A |
| Single pulse avalanche energy | E_{AS} | $T_C = 25$ °C; $I_D = I_{AR}$, $V_{DD} = 50$ V | | 2000 | mJ |
| Avalanche current repetitive | I_{AR} | pulsed width limited by T_J max. | | 15 | A |
| Peak diode recovery voltage slope | $dV/dt^{(2)}$ | | | 15 | V/ μ s |
| Continuous drain current | I_D | $T_C = 25$ °C | $V_{GS} = 10$ V | 52 | A |
| | | $T_C = 80$ °C | | 41 | |
| Power dissipation | P_D | $T_C = 25$ °C | | 284 | W |
| | | $T_C = 80$ °C | | 159 | |
| Q3, Q4 WARP IGBT | | | | | |
| Collector to emitter voltage | V_{CES} | | | 600 | V |
| Gate to emitter voltage | V_{GES} | | | 20 | |
| Pulsed collector current | I_{CM} | | | 200 | A |
| Clamped inductive load current | I_{LM} | | | 200 | |
| Continuous collector current | I_C | $T_C = 25$ °C | | 67 | |
| | | $T_C = 80$ °C | | 43 | |
| Power dissipation | P_D | $T_C = 25$ °C | | 211 | W |
| | | $T_C = 80$ °C | | 118 | |



| ABSOLUTE MAXIMUM RATINGS | | | | |
|---|-----------|----------------------------------|------|-------|
| PARAMETER | SYMBOL | TEST CONDITIONS | MAX. | UNITS |
| D1, D2, AP DIODE OF WARP IGBT | | | | |
| Repetitive peak reverse voltage | V_{RRM} | | 600 | V |
| Diode continuous forward current | I_F | $T_C = 25\text{ }^\circ\text{C}$ | 73 | A |
| | | $T_C = 80\text{ }^\circ\text{C}$ | 48 | |
| Peak diode forward current | I_{FSM} | $T_C = 25\text{ }^\circ\text{C}$ | 260 | |
| Power dissipation | P_D | $T_C = 25\text{ }^\circ\text{C}$ | 143 | W |
| | | $T_C = 80\text{ }^\circ\text{C}$ | 80 | |
| SOURCE DRAIN (MOSFET BODY DIODE) | | | | |
| Continuous source current | I_S | $T_C = 25\text{ }^\circ\text{C}$ | 52 | A |
| Pulsed source current | I_{SM} | $T_C = 25\text{ }^\circ\text{C}$ | 360 | |

Notes

- (1) Pulse width limited by safe operating area
- (2) $I_{SD} < 69\text{ A}$, $dI/dt = 400\text{ A}/\mu\text{s}$, peak $V_{SD} < V_{(BR)DSS}$

| ELECTRICAL SPECIFICATIONS ($T_J = 25\text{ }^\circ\text{C}$ unless otherwise specified) | | | | | | |
|--|--------------------------------|---|------|------|-----------|----------------------------|
| PARAMETER | SYMBOL | TEST CONDITIONS | MIN. | TYP. | MAX. | UNITS |
| Q1, Q2 POWER MOSFET | | | | | | |
| Drain to source breakdown voltage | $V_{(BR)DSS}$ | $V_{GS} = 0\text{ V}$, $I_D = 250\text{ }\mu\text{A}$ | 650 | - | - | V |
| Static drain to source on resistance | $R_{DS(on)}$ | $V_{GS} = 10\text{ V}$, $I_D = 50\text{ A}$ | - | 35 | 44 | $\text{m}\Omega$ |
| | | $V_{GS} = 10\text{ V}$, $I_D = 50\text{ A}$, $T_J = 150\text{ }^\circ\text{C}$ | - | - | 104 | $\text{m}\Omega$ |
| Gate threshold voltage | $V_{GS(th)}$ | $V_{GE} = V_{GS}$, $I_D = 0.25\text{ mA}$ | 2.8 | 4 | 5.4 | V |
| Drain to source leakage current | I_{DSS} | $V_{DS} = 650\text{ V}$, $V_{GS} = 0\text{ V}$ | - | - | 50 | μA |
| | | $V_{DS} = 650\text{ V}$, $V_{GS} = 0\text{ V}$, $T_J = 150\text{ }^\circ\text{C}$ | - | - | 5.0 | mA |
| Gate to source forward leakage | I_{GSS} | $V_{GS} = 25\text{ V}$ | - | - | 100 | nA |
| Gate to source reverse leakage | | $V_{GS} = -25\text{ V}$ | - | - | -100 | |
| Intrinsic gate resistance | R_g | $f = 1\text{ MHz}$, open drain | - | 1.2 | - | Ω |
| Total gate charge | Q_g | $I_D = 35\text{ A}$ | - | 200 | - | nC |
| Gate to source charge | Q_{gs} | $V_{DD} = 520\text{ V}$ | - | 60 | - | |
| Gate to drain (Miller) charge | Q_{gd} | $V_{GS} = 10\text{ V}$ | - | 70 | - | |
| Turn-on delay time | $t_{d(on)}$ | $V_{DD} = 325\text{ V}$ $L = 500\text{ }\mu\text{H}$, $I_D = 40\text{ A}$ $R_g = 5\text{ }\Omega$, $V_{GS} = 10\text{ V}$, $T_J = 125\text{ }^\circ\text{C}$ | - | 165 | - | ns |
| Rise time | t_r | | - | 44 | - | |
| Turn-off delay time | $t_{d(off)}$ | | - | 148 | - | |
| Fall time | t_f | | - | 30 | - | |
| Input capacitance | C_{iss} | $V_{GS} = 0\text{ V}$ | - | 9800 | - | pF |
| Output capacitance | C_{oss} | $V_{DS} = 100\text{ V}$, $f = 1\text{ MHz}$ | - | 200 | - | |
| SOURCE DRAIN (MOSFET BODY DIODE) | | | | | | |
| Forward voltage | V_{SD} | $I_S = 34\text{ A}$, $V_{GS} = 0\text{ V}$ | - | - | 1.0 | V |
| Q3, Q4 WARP IGBT | | | | | | |
| Collector to emitter breakdown voltage | $V_{(BR)CES}$ | $V_{GE} = 0\text{ V}$, $I_C = 250\text{ }\mu\text{A}$ | 600 | - | - | V |
| Collector to emitter voltage | $V_{CE(on)}$ | $V_{GE} = 15\text{ V}$, $I_D = 25\text{ A}$ | - | 2.18 | 2.83 | |
| | | $V_{GE} = 15\text{ V}$, $I_C = 25\text{ A}$, $T_J = 150\text{ }^\circ\text{C}$ | - | 1.75 | 2.34 | |
| Gate threshold voltage | $V_{GE(th)}$ | $V_{CE} = V_{GE}$, $I_C = 0.25\text{ mA}$ | 2.8 | 4.9 | 6.2 | V |
| Temperature coefficient of threshold voltage | $\Delta V_{GE(th)}/\Delta T_J$ | $V_{CE} = V_{GE}$, $I_C = 1\text{ mA}$ ($25\text{ }^\circ\text{C}$ to $125\text{ }^\circ\text{C}$) | - | -12 | - | $\text{mV}/^\circ\text{C}$ |
| Forward transconductance | g_{fe} | $V_{CE} = 20\text{ V}$, $I_C = 25\text{ A}$ | - | 49 | - | S |
| Zero gate voltage collector current | I_{CES} | $V_{GE} = 0\text{ V}$, $V_{CE} = 600\text{ V}$ | - | - | 250 | μA |
| | | $V_{GE} = 0\text{ V}$, $V_{CE} = 600\text{ V}$, $T_J = 125\text{ }^\circ\text{C}$ | - | - | 5.0 | mA |
| Gate to emitter leakage current | I_{GES} | $V_{GE} = \pm 20\text{ V}$, $V_{CE} = 0\text{ V}$ | - | - | ± 100 | nA |
| D1, D2, AP DIODE OF WARP IGBT | | | | | | |
| Forward voltage drop | V_{FM} | $I_F = 25\text{ A}$ | - | 1.3 | 1.41 | V |
| | | $I_F = 25\text{ A}$, $T_J = 150\text{ }^\circ\text{C}$ | - | 1.11 | 1.29 | |



| SWITCHING CHARACTERISTICS ($T_J = 25\text{ }^\circ\text{C}$ unless otherwise specified) | | | | | | |
|---|-----------|--|------|------|------|-------|
| PARAMETER | SYMBOL | TEST CONDITIONS | MIN. | TYP. | MAX. | UNITS |
| Q3, Q4 WARP IGBT | | | | | | |
| Total gate charge (turn-on) | Q_g | $I_C = 25\text{ A}$ | - | 175 | - | nC |
| Gate to emitter charge (turn-on) | Q_{ge} | $V_{CC} = 400\text{ V}$ | - | 27 | - | |
| Gate to collector charge (turn-on) | Q_{gc} | $V_{GE} = 15\text{ V}$ | - | 71 | - | |
| Turn-on switching loss | E_{on} | $I_C = 25\text{ A}$ | - | 0.21 | - | mJ |
| Turn-off switching loss | E_{off} | $V_{CC} = 400\text{ V}, V_{GE} = 15\text{ V}$ | - | 0.15 | - | |
| Total switching loss | E_{tot} | $R_g = 5\text{ }\Omega, L = 500\text{ }\mu\text{H}$ | - | 0.36 | - | |
| Turn-on switching loss | E_{on} | $I_C = 25\text{ A}$ | - | 0.33 | - | mJ |
| Turn-off switching loss | E_{off} | $V_{CC} = 400\text{ V}, V_{GE} = 15\text{ V}$ | - | 0.36 | - | |
| Total switching loss | E_{tot} | $R_g = 5\text{ }\Omega, T_J = 125\text{ }^\circ\text{C}, L = 500\text{ }\mu\text{H}$ | - | 0.69 | - | |
| D1, D2, AP DIODE OF WARP IGBT | | | | | | |
| Diode reverse recovery time | t_{rr} | $V_{RR} = 400\text{ V}$ | - | 118 | - | ns |
| Diode peak reverse current | I_{rr} | $I_F = 25\text{ A}, T_J = 125\text{ }^\circ\text{C}$ | - | 13.5 | - | A |
| Diode recovery charge | Q_{rr} | $di/dt = 200\text{ A}/\mu\text{s}$ | - | 760 | - | nC |
| SOURCE DRAIN (MOSFET BODY DIODE) | | | | | | |
| Diode reverse recovery time | t_{rr} | $I_{SD} = 34.5\text{ A}$ | - | 563 | - | ns |
| Diode reverse current | I_{rr} | $V_{DD} = 100\text{ V}$ | - | 35 | - | A |
| Diode recovery charge | Q_{rr} | $di/dt = 100\text{ A}/\mu\text{s}$ | - | 9500 | - | nC |

| THERMISTOR ELECTRICAL CHARACTERISTICS ($T_J = 25\text{ }^\circ\text{C}$ unless otherwise specified) | | | | |
|---|--------|--|------|----------|
| PARAMETER | SYMBOL | TEST CONDITIONS | TYP. | UNITS |
| Resistance | R | $T_J = 25\text{ }^\circ\text{C}$ | 5000 | Ω |
| B Value | B | $T_J = 125\text{ }^\circ\text{C}/50\text{ }^\circ\text{C}$ | 3375 | K |

| MECHANICAL SPECIFICATIONS | | | | | | |
|---|------------|------|------|------|---------------------------|--|
| PARAMETER | SYMBOL | MIN. | TYP. | MAX. | UNITS | |
| Junction to case Q1, Q2 POWER MOSFET thermal resistance (per switch) | R_{thJC} | - | - | 0.44 | $^\circ\text{C}/\text{W}$ | |
| Junction to case Q3, Q4 WARP IGBT thermal resistance (per switch) | | - | - | 0.59 | | |
| Junction to case D1, D2, AP diode of WARP IGBT thermal resistance (per diode) | | - | - | 0.87 | | |
| Case to sink, flat, greased surface (per module) | R_{thCS} | - | 0.05 | - | | |
| Mounting torque $\pm 10\%$ to heatsink ⁽¹⁾ | | - | - | 4 | Nm | |
| Weight | | - | 65 | - | g | |

Note

⁽¹⁾ A mounting compound is recommended and the torque should be rechecked after a period of 3 hours to allow for the spread of the compound. Lubricated threads.

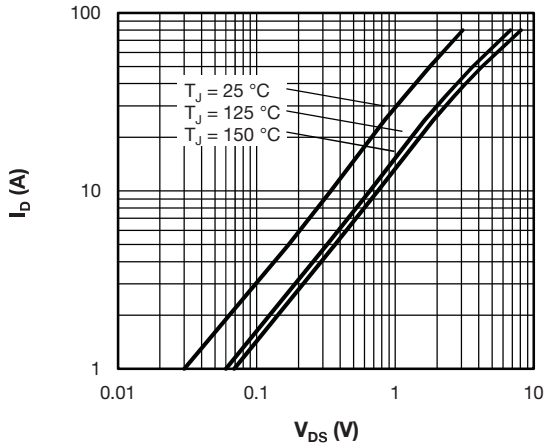


Fig. 1 - Power MOSFET Q1 - Q2 Typical Output Characteristics, $V_{GS} = 10\text{ V}$

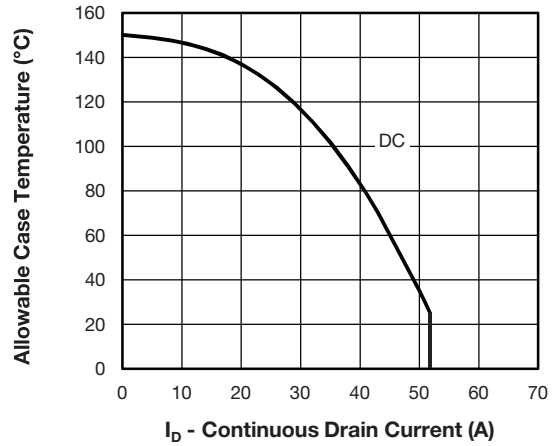


Fig. 4 - Power MOSFET Q1 - Q2 Maximum Continuous Drain Current vs. Case Temperature, $V_{GS} = 10\text{ V}$

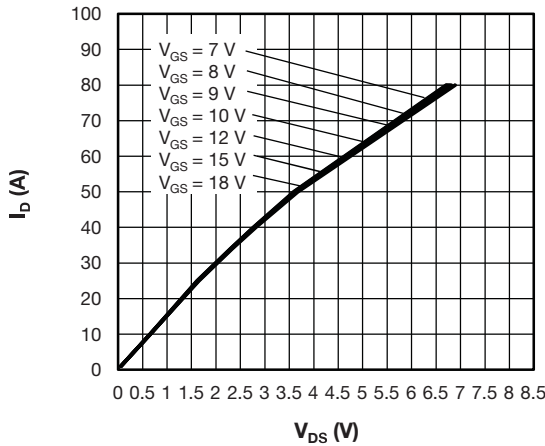


Fig. 2 - Power MOSFET Q1 - Q2 Typical Output Characteristics, $T_J = 125\text{ °C}$

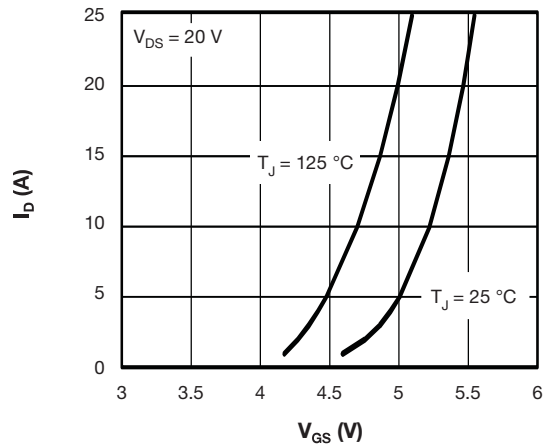


Fig. 5 - Power MOSFET Q1 - Q2 Typical Transfer Characteristics

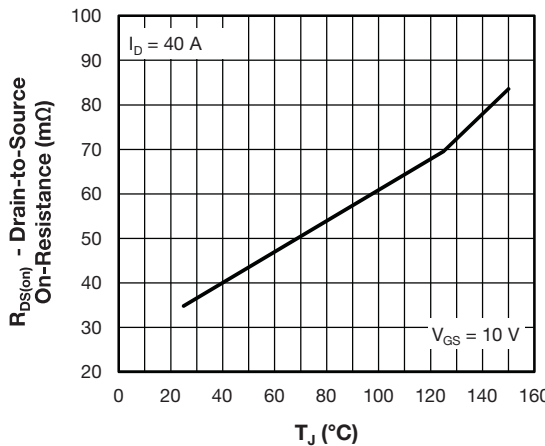


Fig. 3 - Power MOSFET Q1 - Q2 Typical Drain-to-Source On-Resistance vs. Temperature

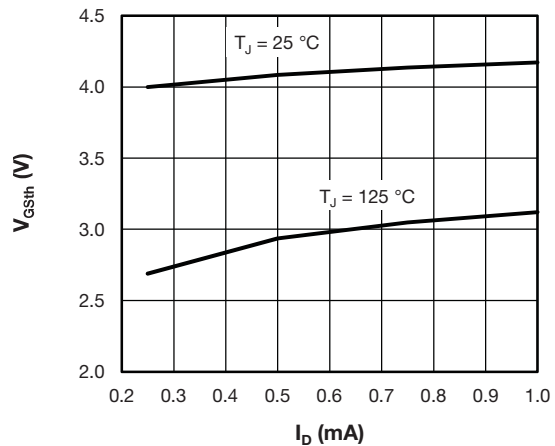


Fig. 6 - Power MOSFET Q1 - Q2 Typical Gate Threshold Voltage

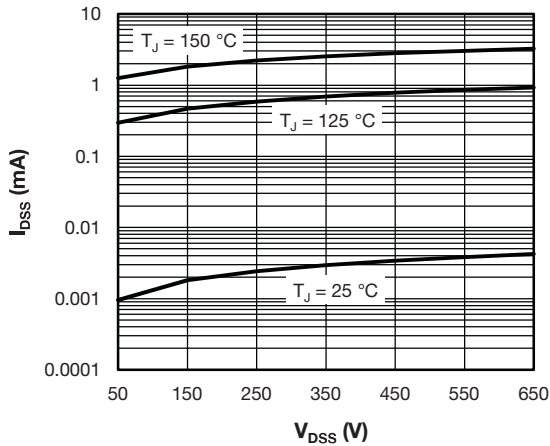


Fig. 7 - Power MOSFET Q1 - Q2 Typical Zero Gate Voltage Drain Current

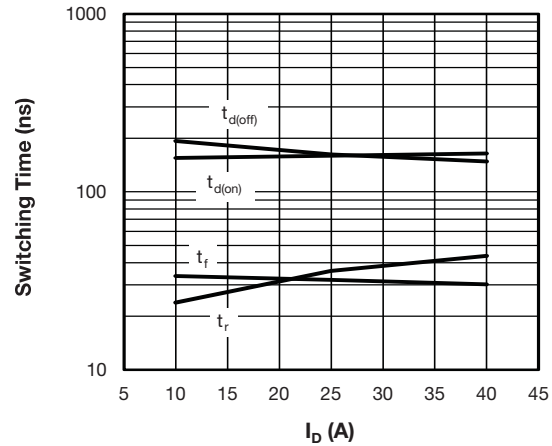


Fig. 9 - Power MOSFET Q1 - Q2 Typical Switching Time vs. I_D (with freewheeling diode 15ETH06), $T_J = 125\text{ }^\circ\text{C}$, $V_{DD} = 325\text{ V}$, $R_g = 5\text{ }\Omega$, $V_{GS} = 10\text{ V}$, $L = 500\text{ }\mu\text{H}$

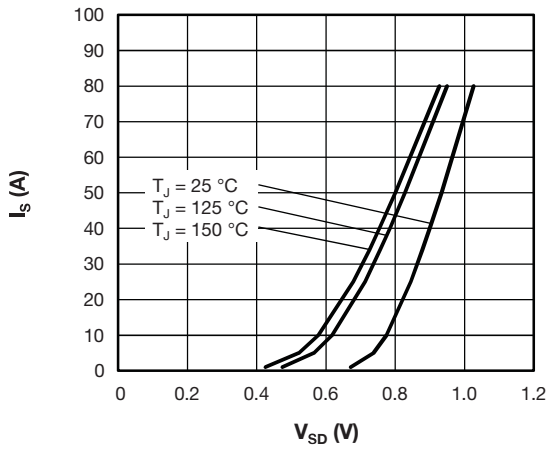


Fig. 8 - Power MOSFET Q1 - Q2 Typical Bodydiode Source-to-Drain Current Characteristics

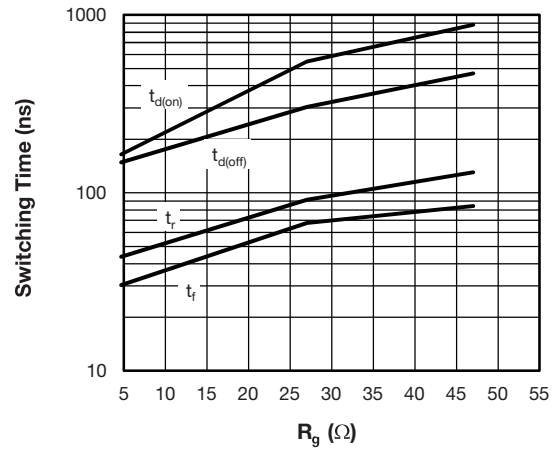


Fig. 10 - Power MOSFET Q1 - Q2 Typical Switching Time vs. R_g (with freewheeling diode 15ETH06), $T_J = 125\text{ }^\circ\text{C}$, $V_{DD} = 325\text{ V}$, $I_D = 40\text{ A}$, $V_{GS} = 10\text{ V}$, $L = 500\text{ }\mu\text{H}$

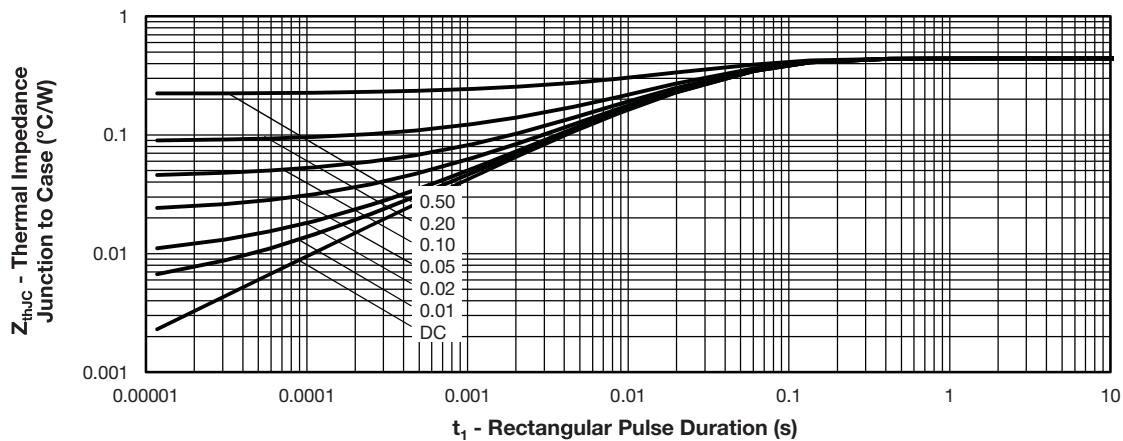


Fig. 11 - Maximum Thermal Impedance Z_{thJC} Characteristics (Q1 - Q2 Power MOSFET)

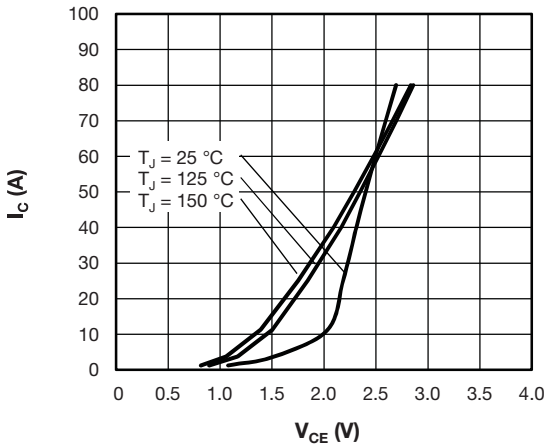


Fig. 12 - Q3 - Q4 IGBT Typical Output Characteristics, $V_{GE} = 15\text{ V}$

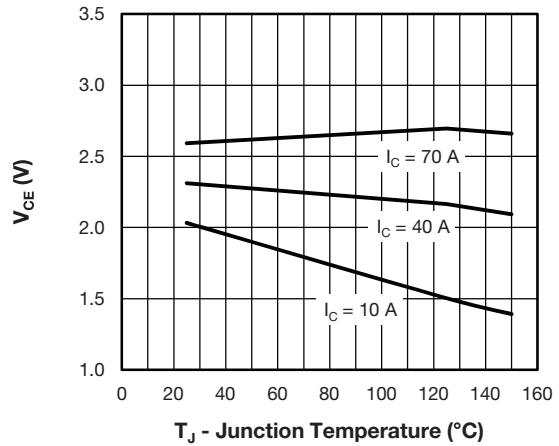


Fig. 15 - Q3 - Q4 IGBT Typical Collector to Emitter Voltage vs. Junction Temperature, $V_{GE} = 15\text{ V}$

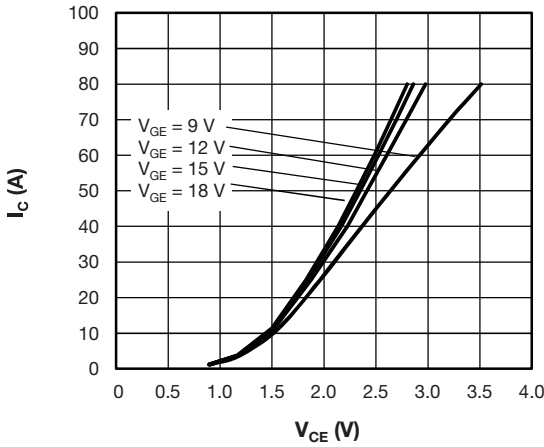


Fig. 13 - Q3 - Q4 IGBT Typical Output Characteristics, $T_J = 125^\circ\text{C}$

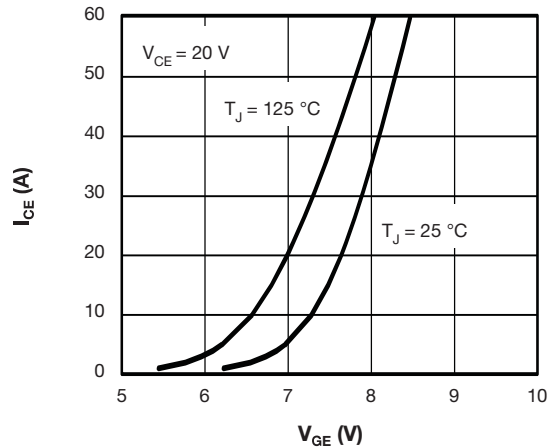


Fig. 16 - Q3 - Q4 IGBT Typical Transfer Characteristics

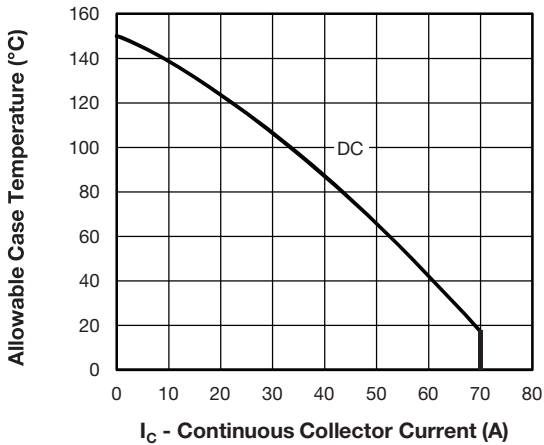


Fig. 14 - Q3 - Q4 IGBT Maximum Continuous Collector Current vs. Case Temperature

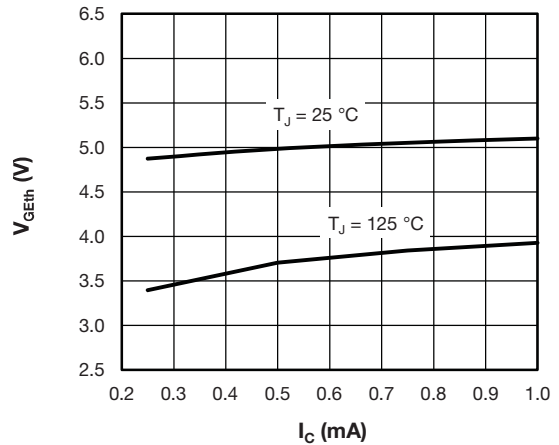


Fig. 17 - Q3 - Q4 IGBT Typical Gate Threshold Voltage

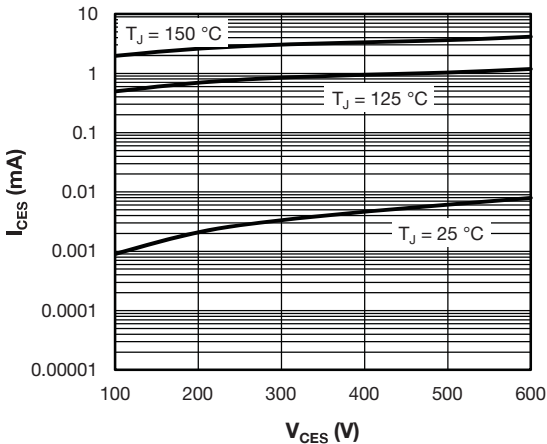


Fig. 18 - Q3 - Q4 IGBT Typical Trench Zero Gate Voltage Collector Current

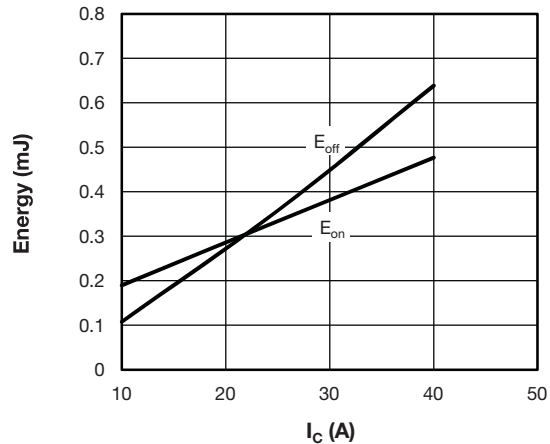


Fig. 21 - Q3 - Q4 IGBT Typical Energy Loss vs. I_C (with freewheeling D1 - D2 antiparallel diode), $T_J = 125\text{ }^\circ\text{C}$, $V_{CC} = 400\text{ V}$, $R_g = 5\ \Omega$, $V_{GE} = 15\text{ V}$, $L = 500\ \mu\text{H}$

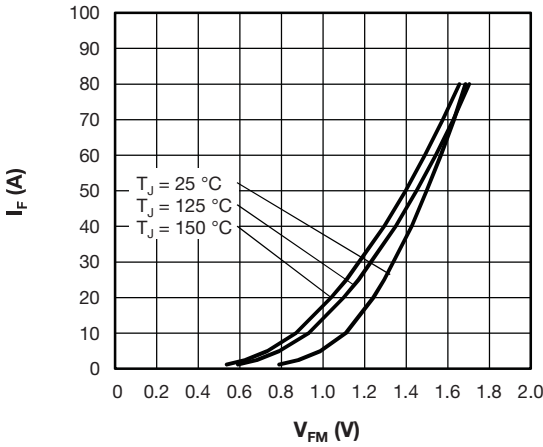


Fig. 19 - D1 - D2 Antiparallel Diode Typical Forward Characteristics

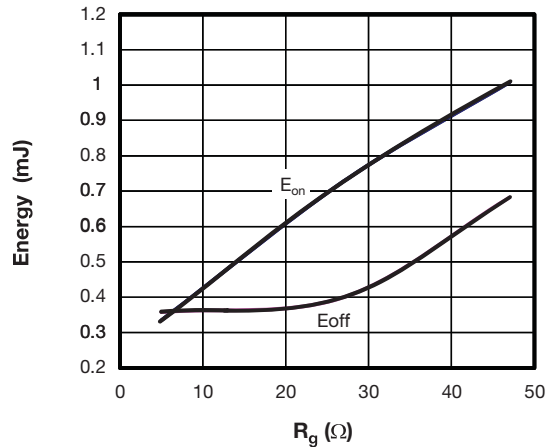


Fig. 22 - Q3 - Q4 IGBT Typical Energy Loss vs. R_g (with freewheeling D1 - D2 antiparallel diode), $T_J = 125\text{ }^\circ\text{C}$, $V_{CC} = 400\text{ V}$, $V_{GE} = 15\text{ V}$, $L = 500\ \mu\text{H}$, $I_C = 25\text{ A}$

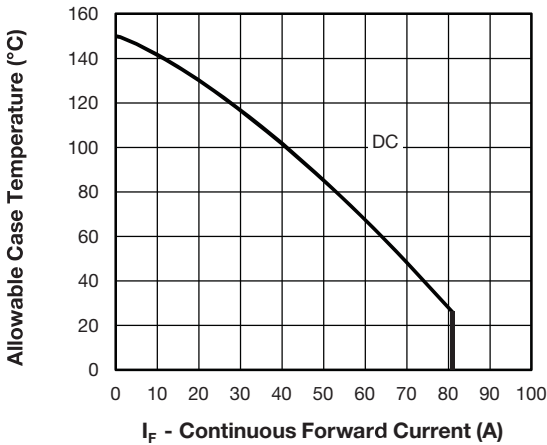


Fig. 20 - D1 - D2 Antiparallel Diode Maximum Forward Current vs. Case Temperature

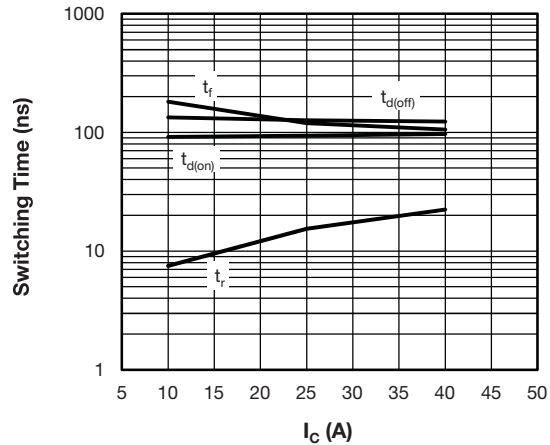


Fig. 23 - Q3 - Q4 IGBT Typical Switching Time vs. I_C (with freewheeling D1 - D2 antiparallel diode), $T_J = 125\text{ }^\circ\text{C}$, $V_{CC} = 400\text{ V}$, $R_g = 5\ \Omega$, $V_{GE} = 15\text{ V}$, $L = 500\ \mu\text{H}$

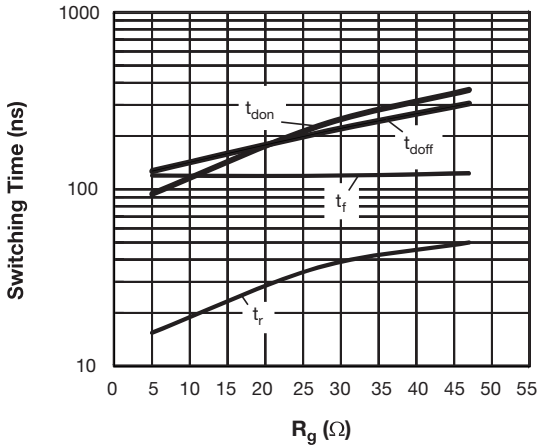


Fig. 24 - Q3 - Q4 IGBT Typical Switching Time vs. R_g (with freewheeling D1 - D2 antiparallel diode), $T_J = 125\text{ }^\circ\text{C}$, $V_{CC} = 400\text{ V}$, $V_{GE} = 15\text{ V}$, $L = 500\text{ }\mu\text{H}$, $I_C = 25\text{ A}$

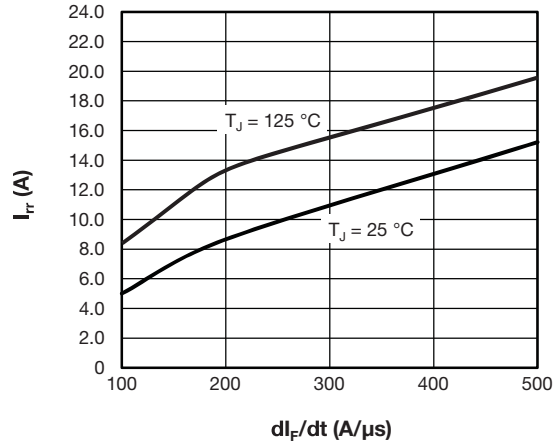


Fig. 26 - D1 - D2 Antiparallel Diode Typical Reverse Recovery Current vs. dI_F/dt , $V_{RR} = 400\text{ V}$, $I_F = 25\text{ A}$

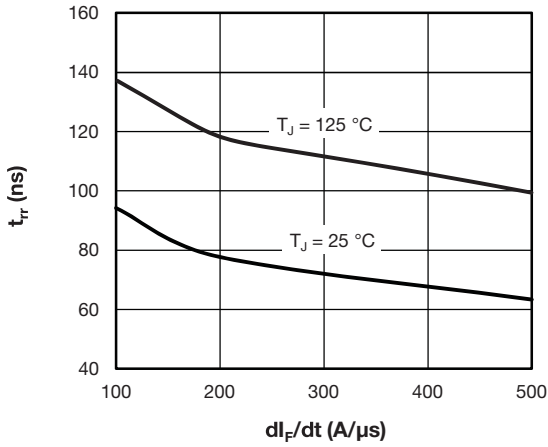


Fig. 25 - D1 - D2 Antiparallel Diode Typical Reverse Recovery Time vs. dI_F/dt , $V_{RR} = 400\text{ V}$, $I_F = 25\text{ A}$

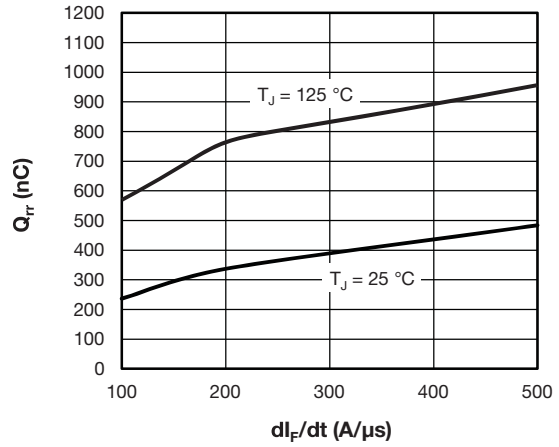


Fig. 27 - D1 - D2 Antiparallel Diode Typical Reverse Recovery Charge vs. dI_F/dt , $V_{RR} = 400\text{ V}$, $I_F = 25\text{ A}$

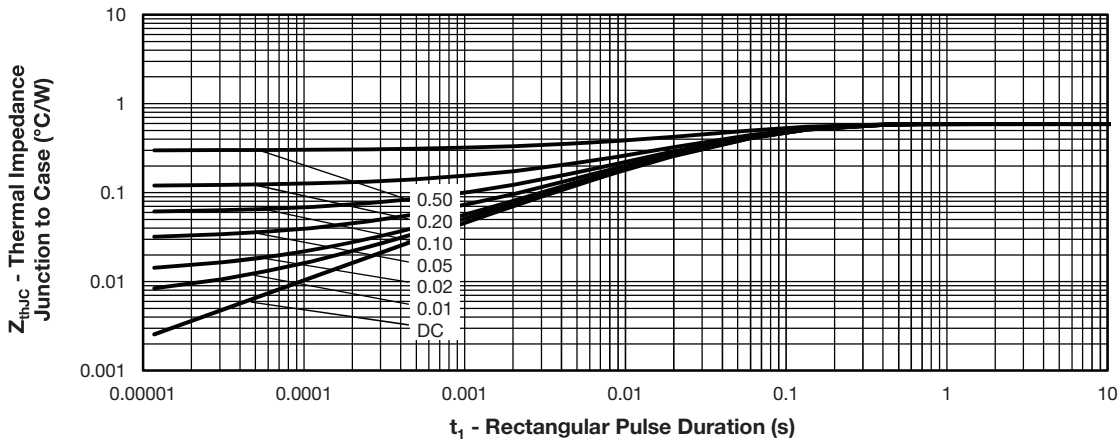


Fig. 28 - Maximum Thermal Impedance Z_{thJC} Characteristics (Q1 - Q2 WARP IGBT)

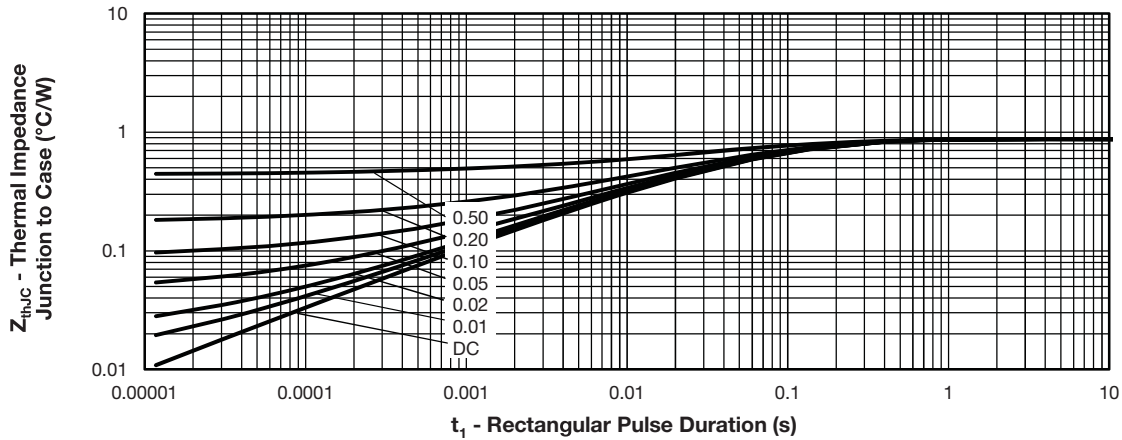


Fig. 29 - Maximum Thermal Impedance Z_{thJC} Characteristics (D1 - D2 Antiparallel Diode)

ORDERING INFORMATION TABLE

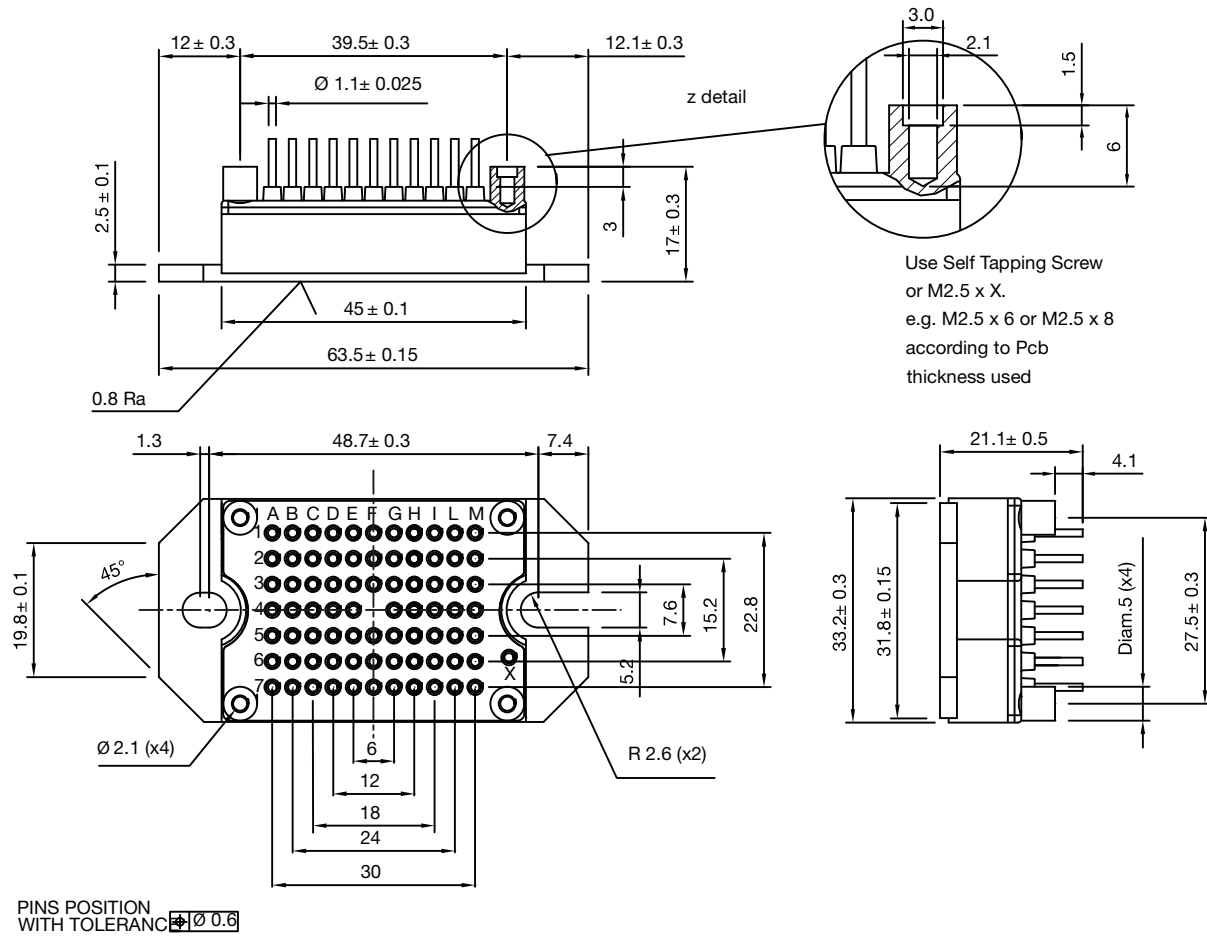
| | | | | | | | |
|-------------|------------|-----------|-----------|------------|----------|-----------|----------|
| Device code | VS- | 40 | MT | 060 | W | FH | T |
| | ① | ② | ③ | ④ | ⑤ | ⑥ | ⑦ |

- 1** - Vishay Semiconductors Product
- 2** - Current rating (40 = 40 A)
- 3** - MTP package
- 4** - Voltage code (060 = 600 V)
- 5** - Speed/type (W = Warp IGBT)
- 6** - Circuit configuration (FH = Full bridge MOSFET, IGBT)
- 7** - Thermistor

| CIRCUIT CONFIGURATION | | |
|--------------------------|----------------------------|-----------------|
| CIRCUIT | CIRCUIT CONFIGURATION CODE | CIRCUIT DRAWING |
| Full bridge MOSFET, IGBT | FH | |



DIMENSIONS in millimeters





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